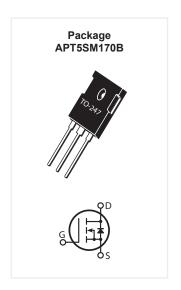


PRELIMINARY 1700V, 5A, 0.95Ω

Silicon Carbide N-Channel Power MOSFET

DESCRIPTION

Silicon carbide (SiC) power MOSFET product line from Microsemi increase your performance over silicon MOSFET and silicon IGBT solutions while lowering your total cost of ownership for high-voltage applications.



FEATURES / TYPICAL APPLICATIONS

SiC MOSFET Features:

- · Low capacitances and low gate charge
- Fast switching speed due to low internal gate resistance (ESR)
- Stable operation at high junction temperature, Tj(max) = +175C
- · Fast and reliable body diode

SiC MOSFET Benefits:

- High efficiency to enable lighter/compact system
- · Simple to drive and easy to parallel
- Improved thermal capabilities and lower switching losses
- Eliminates the need of external Free Wheeling Diode
- · Lower system cost of ownership

Applications:

- PV inverter, converter and industrial motor drives
- · Smart grid transmission & distribution
- · Induction heating, and welding
- · H/EV powertrain and EV charger
- · Power supply and distribution

MAXIMUM RATINGS

Symbol	Parameter	Ratings	Unit
V _{DSS}	Drain Source Voltage	1700	V
	Continuous Drain Current @ T _c = 25°C	5	
' _D	Continuous Drain Current @ T _c = 100°C	3.5	А
I _{DM}	Pulsed Drain Current ^①	8	
V _{GS}	Gate-Source Voltage	-10 to +25	V
В	Total Power Dissipation @ T _c = 25°C	65	W
P _D	Linear Derating Factor	0.43	W/°C

THERMAL AND MECHANICAL CHARACTERISTICS

Symbol	Characteristic	Min	Тур	Max	Unit
$R_{\theta JC}$	Junction to Case Thermal Resistance		1.7	2.3	°C/W
T _i	Operating Junction Temperature	-55		175	
T _{stg}	Storage Junction Temperature Range	-55		150	°C
T _L	Soldering Temperature for 10 Seconds (1.6mm from case)			260	
Torque	Mounting Torque (TO-247 Package), 6-32 or M3 screw			10	in·lbf
				1.1	N·m

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STATIC CHARACTERISTICS

Symbol	Parameter	Test Conditions		Min	Тур	Max	Unit
V _{(BR)DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_{D} = 100\mu A$		1700			V
R _{DS(on)}	Drain-Source On Resistance②	$V_{GS} = 20V, I_{D}$		950	1250	mΩ	
$V_{GS(th)}$	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 0.5 mA$		1.8	3.2		V
$\Delta V_{GS(th)}/\Delta T_{J}$	Threshold Voltage Temperature Coefficient				-7.6		mV/°C
	Zero Gate Voltage Drain Current	V _{DS} = 1700V	T _J = 25°C			100	
DSS		V _{GS} = 0V	T _J = 150°C			250	μA
I _{GSS}	Gate-Source Leakage Current	V _{GS} = +20V / -10V				±100	nA

 $T_J = 25$ °C unless otherwise specified

DYNAMIC CHARACTERISTICS

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
C _{iss}	Input Capacitance	V = 0V V = 1000V		249		
C _{rss}	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{GS} = 1000V$		3		pF
C _{oss}	Output Capacitance	f = 1MHz		15		
Q_g	Total Gate Charge	V _{GS} = 0/20V		21		
Q _{gs}	Gate-Source Charge	V _{DS} = 850V		5		nC
Q_{gd}	Gate-Drain Charge	I _D = 2.5A		8		
t _{d(on)}	Turn-On Delay Time	V _{ps} = 850V		4		
t _r	Current Rise Time	$V_{GS} = 0/20V$		2		ns
t _{d(off)}	Turn-Off Delay Time	I _D = 2.5A		7		
t,	Current Fall Time	$R_{_{\rm G}} = 2.5\Omega$ ³		4		1
E _{on2}	Turn-On Switching Energy [®]	L = 115 μH		82		1
E _{off}	Turn-Off Switching Energy	T _c = 25°C		37		μJ
t _{d(on)}	Turn-On Delay Time	V _{DS} = 850V		3		
t _r	Current Rise Time	$V_{GS} = 0/20V$		2		
t _{d(off)}	Turn-Off Delay Time	$I_D = 2.5A$ $R_G = 2.5 \Omega^{3}$		8		ns
t,	Current Fall Time			5		
E _{on2}	Turn-On Switching Energy [®]	L = 115 μH		87		
E _{off}	Turn-Off Switching Energy	T _c = 150°C		39		μJ
ESR	Equivalent Series Resistance	f = 1MHz, 25mV, Drain Short		1.43		Ω

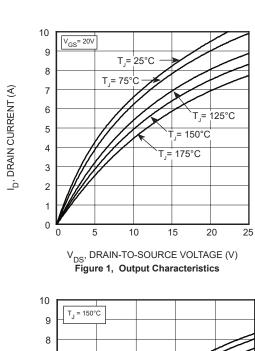
Source-Drain Diode Characteristics

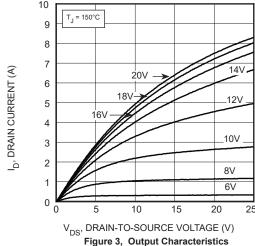
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V _{SD}	Diode Forward Voltage	$I_{SD} = 2.5A, V_{GS} = 0V$		4		V
t _{rr}	Reverse Recovery Time	I _{SD} = 2.5A, V _{DD} = 850V dI/dt = -1000A/μs		14		ns
Q _{rr}	Reverse Recovery Charge			24		nC
I	Reverse Recovery Current			3.6		Α

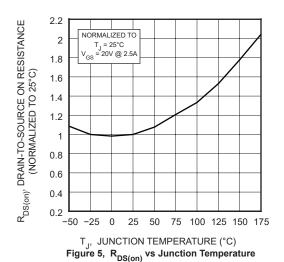
T_J = 25°C unless otherwise specified

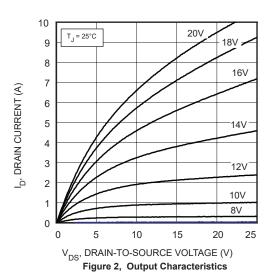
- ① Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature
- ② Pulse test: Pulse Width < 380 μ s, duty cycle < 2%.
- $\begin{tabular}{ll} \hline \end{tabular} \begin{tabular}{ll} \hline \end{t$
- \bigoplus E_{on2} includes energy of free wheeling diode.

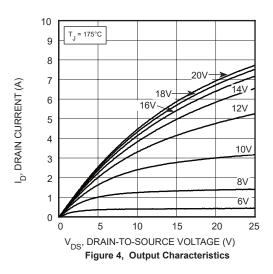


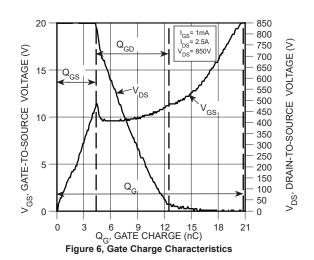


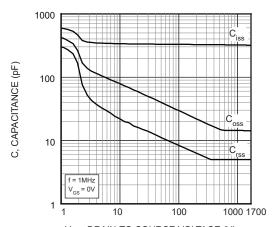




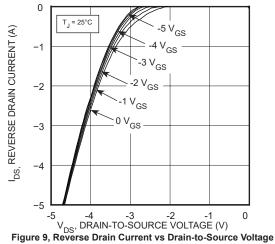




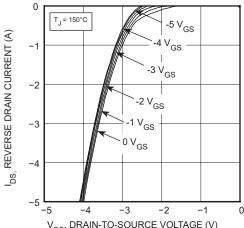




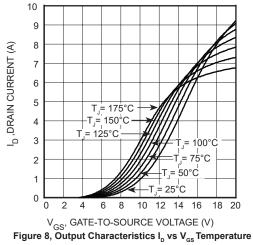
 V_{DS} , DRAIN-TO-SOURCE VOLTAGE (V) Figure 7, Capacitance vs Drain-to-Source Voltage

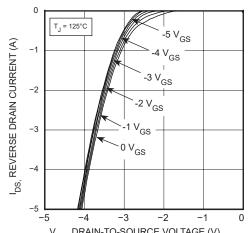


Third Quadrant Conduction



 ${\rm V_{DS'}, DRAIN\text{-}TO\text{-}SOURCE\ VOLTAGE\ (V)}$ Figure 11, Reverse Drain Current vs Drain-to-Source Voltage **Third Quadrant Conduction**





 ${\rm V_{DS}, DRAIN\text{-}TO\text{-}SOURCE\ VOLTAGE\ (V)}$ Figure 10, Reverse Drain Current vs Drain-to-Source Voltage **Third Quadrant Conduction**

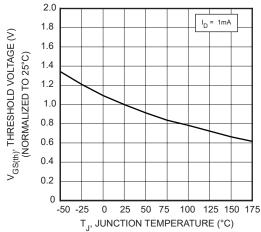
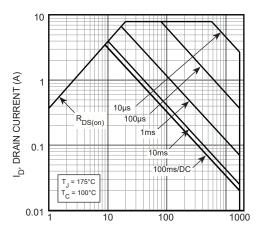


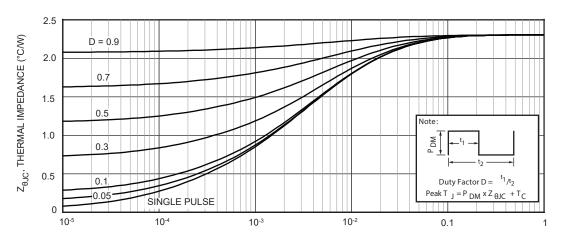
Figure 12, Threshold Voltage vs Temperature

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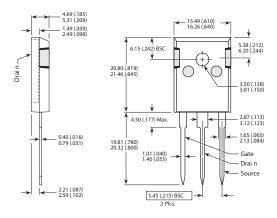


 $V_{\rm DS}$, DRAIN-TO-SOURCE VOLTAGE (V) Figure 13, Forward Safe Operating Area



RECTANGULAR PULSE DURATION (SECONDS)
Figure 14, Maximum Effective Transient Thermal Impedance, Junction-To-Case vs Pulse Duration

TO-247 (B) Package Outline



Dimensions in Millimeters (Inches)

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